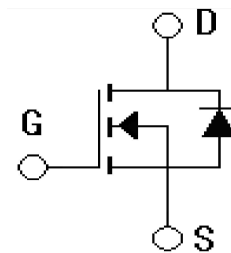
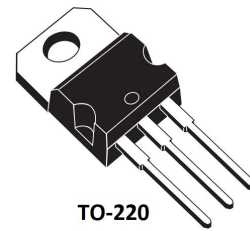


Features

- $V_{DSS}=85V, I_D=210A$
 $R_{DS(ON)} < 4.95m\Omega @ V_{GS}=10V$
- High density cell design
for ultra low $R_{ds(on)}$
- Fully characterized
avalanche voltage and current
- Good stability and
uniformity with high EAS
- Excellent package for
good heat dissipation
- Special process technology
for high ESD capability



Applications

- Automotive applications
- Hard switched and high frequency circuits
- UPS

Absolute Ratings ($T_c=25^\circ C$)

Parameter	Symbol	Value	Unit
Drain-Source Voltage	V_{DSS}	85	V
Drain Current -continuous	$I_D, T=25^\circ C$ $T=100^\circ C$	210(note 5)	A
		148	A
Drain Current - pulse	I_{DM}	850	A
Gate-Source Voltage	V_{GSS}	± 20	V
Single Pulsed Avalanche Energy (note 3)	E_{AS}	1800	mJ
Power Dissipation	PD $TC=25^\circ C$	300	W
		2.0	W/ $^\circ C$
Operating and Storage Temperature Range	T_j, T_{STG}	-55~+175	$^\circ C$
Peak Diode Recovery dv/dt (Note 4)	dv/dt	5	V/ns

*Drain current limited by maximum junction temperature

Electrical Characteristics($T_{CASE}=25^\circ C$ unless otherwise specified)

Parameter	Symbol	Tests conditions	Min	Type	Max	Units
Off-Characteristics						

Drain-Source Voltage	BV_{DSS}	$I_D=250\mu A, V_{GS}=0V$	85	-	-	V
Drain cut-off current	I_{DSS}	$V_{DS}=85V, V_{GS}=0V$ $T_j=25^\circ C$	-	-	1	μA
Gate-body leakage current, forward	I_{GSSF}	$V_{DS}=0V, V_{GS}=20V$	-	-	200	nA
Gate-body leakage current, reverse	I_{GSSR}	$V_{DS}=0V, V_{GS}=-20V$	-	-	-200	nA
On-Characteristics						
Gate Threshold Voltage	$V_{GS(th)}$	$V_{DS}=V_{GS}, I_D=250\mu A$	2.0	3.2	4.0	V
Static Drain-Source On-Resistance	$R_{DS(ON)}$	$V_{GS}=10V, I_D=40A$	-	4.1	4.95	m Ω
Forward Transconductance	g_{fs}	$V_{DS}=10V, I_D=20A$	35	-	-	S
Dynamic Characteristics						
Input capacitance	C_{iss}	$V_{DS}=25V,$ $V_{GS}=0V,$ $f=1.0MHz$	-	7600	-	pF
Output capacitance	C_{oss}		-	720	-	pF
Reverse transfer capacitance	C_{rss}		-	346	-	pF

Switching Characteristics						
Turn-On delay time	td(on)	VDD=40V,ID=40A, RG=1.2Ω, VGS=10V (note 2)	-	23	-	ns
Turn-On rise time	tr		-	124	-	ns
Turn-Off delay time	td(off)		-	84	-	ns
Turn-Off Fall time	tf		-	78	-	ns
Total Gate Charge	Qg	VDS=40V, ID=40A, VGS=10V(note 2)	-	140	-	nC
Gate-Source charge	Qgs		-	40	-	nC
Gate-Drain charge	Qgd		-	57	-	nC
Drain-Source Diode Characteristics and Maximum Ratings						
Drain-Source Diode Forward Voltage	VSD	VGS=0V,IS=40A	-	-	1.2	V
Reverse recovery time	trr	VGS=0V,IF=40A dIF/dt=500A/us(note 2)	-	110	-	ns
Reverse recovery charge	Qrr		-	300	-	uC
Forward Turn-On Time	ton	Intrinsic turn-on time is negligible (turn-on is dominated by LS+LD)				

Thermal Characteristic

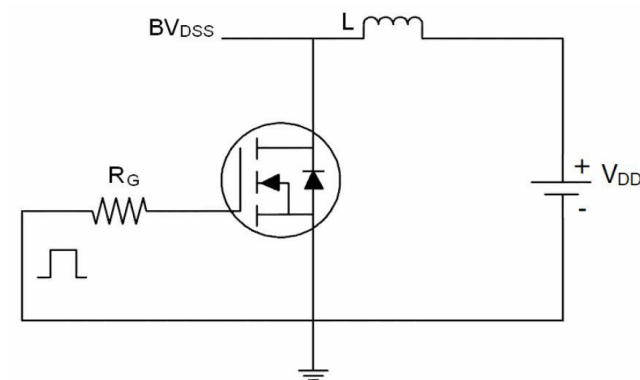
Parameter	Symbol	Value	Unit
Thermal Resistance, Junction-to-Case	$R_{\theta JC}$	0.5	$^{\circ}\text{C/W}$

Notes:

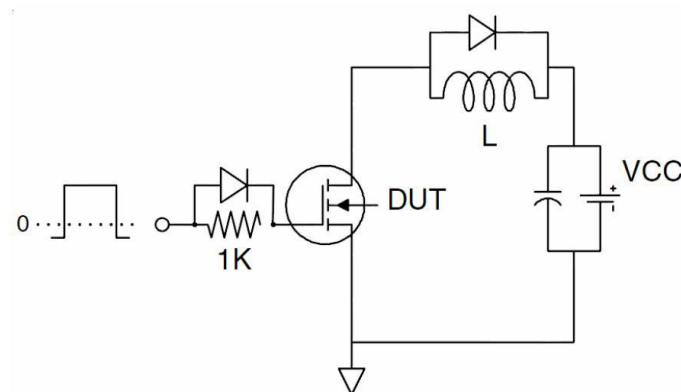
1. Surface Mounted on FR4 Board, $t \leq 10$ sec.
2. Pulse Test: Pulse Width $\leq 400\mu\text{s}$, Duty Cycle $\leq 2\%$.
3. EAS condition: $T_J = 25^{\circ}\text{C}$, $V_{DD} = 42.5\text{V}$, $V_G = 10\text{V}$, $L = 0.5\text{mH}$, $R_g = 25\Omega$
4. $I_{SD} \leq 125\text{A}$, $di/dt \leq 260\text{A}/\mu\text{s}$, $V_{DD} \leq V(BR)_{DSS}$, $T_J \leq 175^{\circ}\text{C}$

Test Circuit

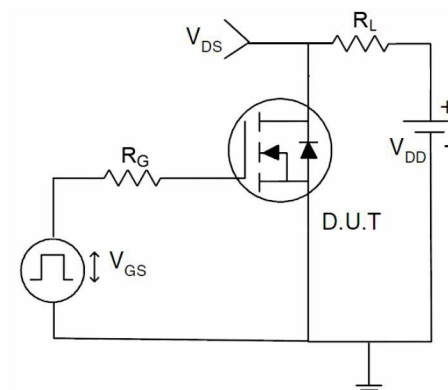
1) E_{AS} test Circuit



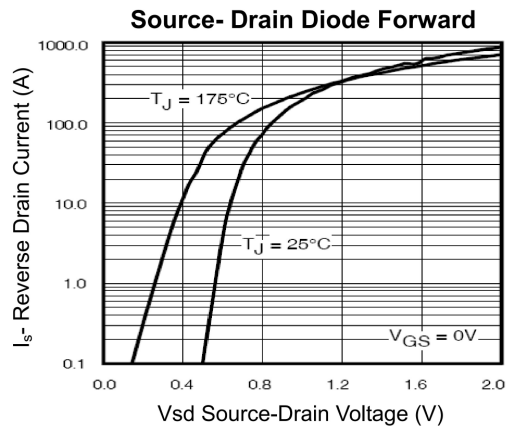
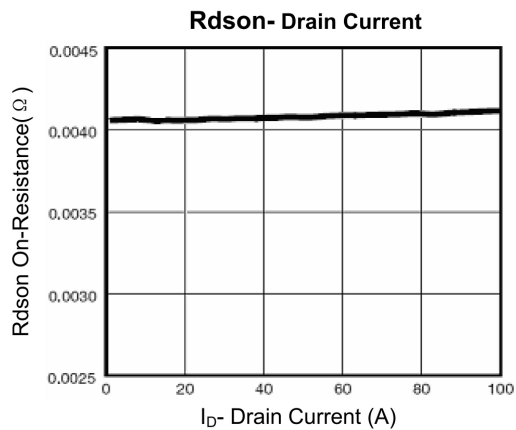
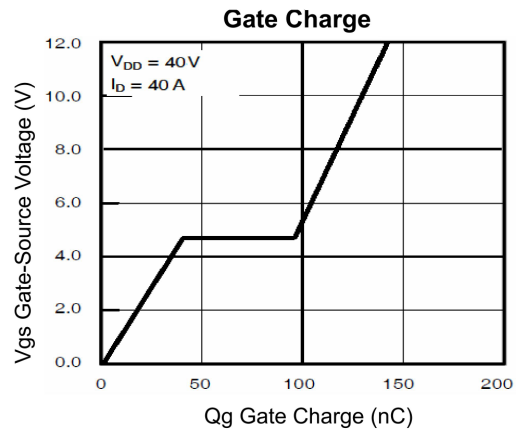
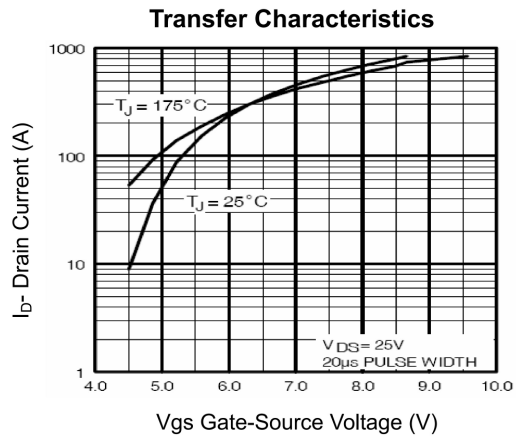
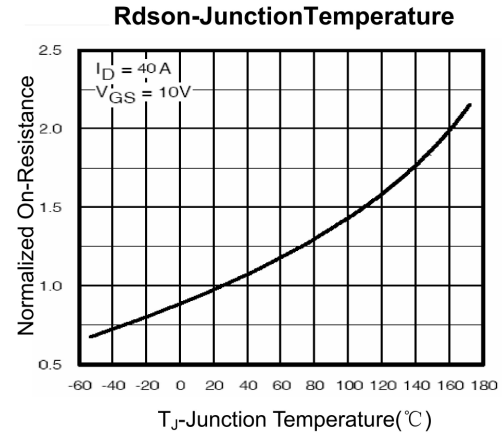
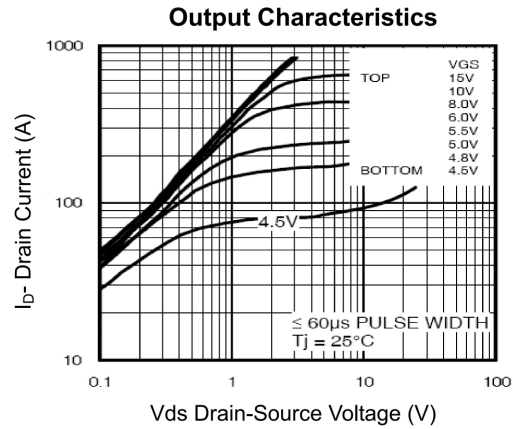
2) Gate charge test Circuit

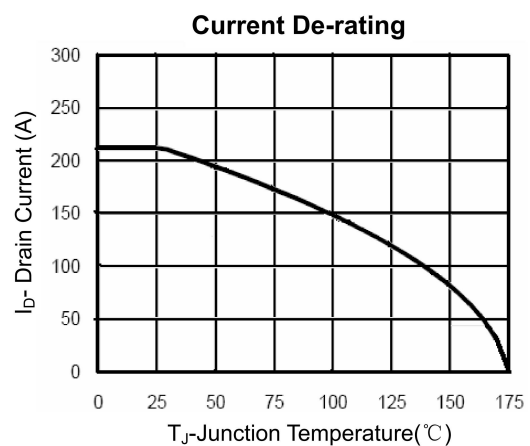
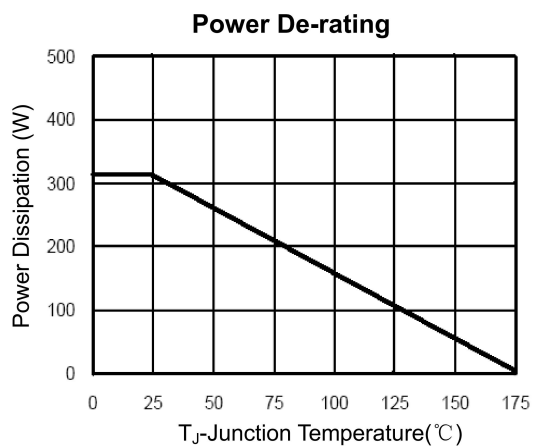
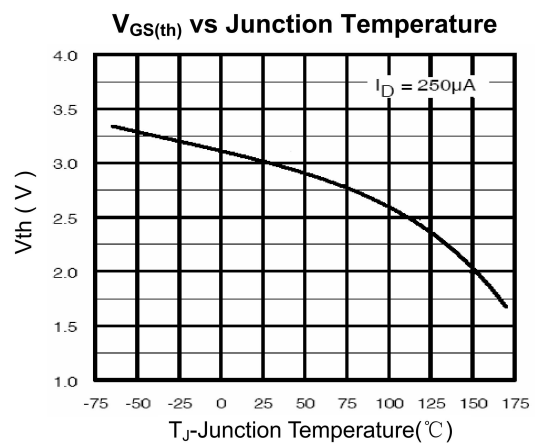
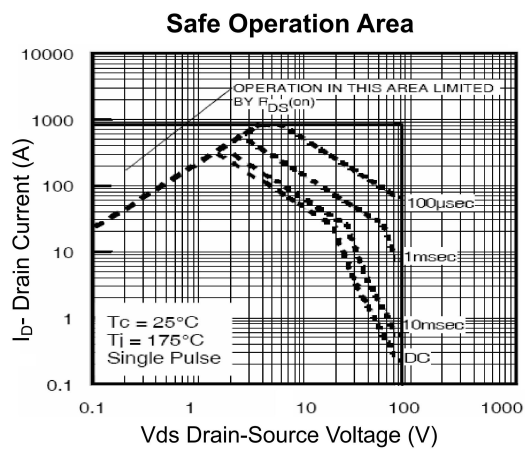
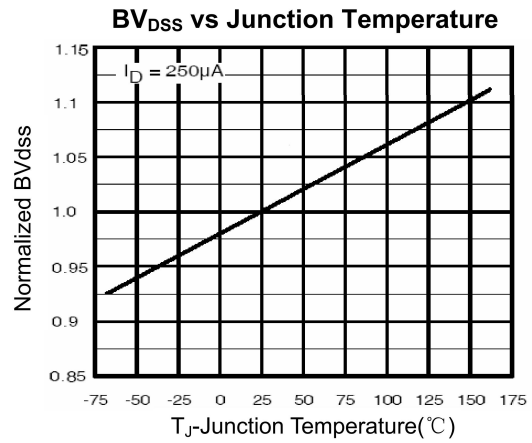
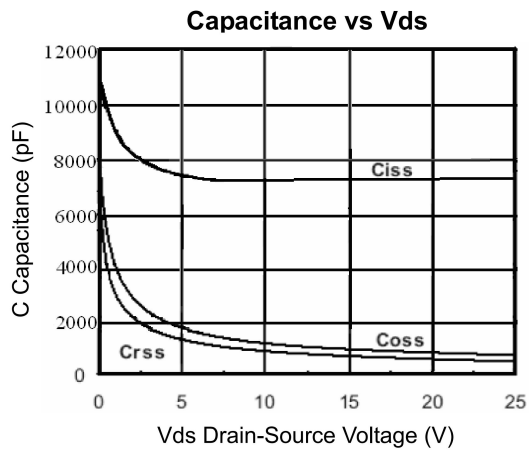


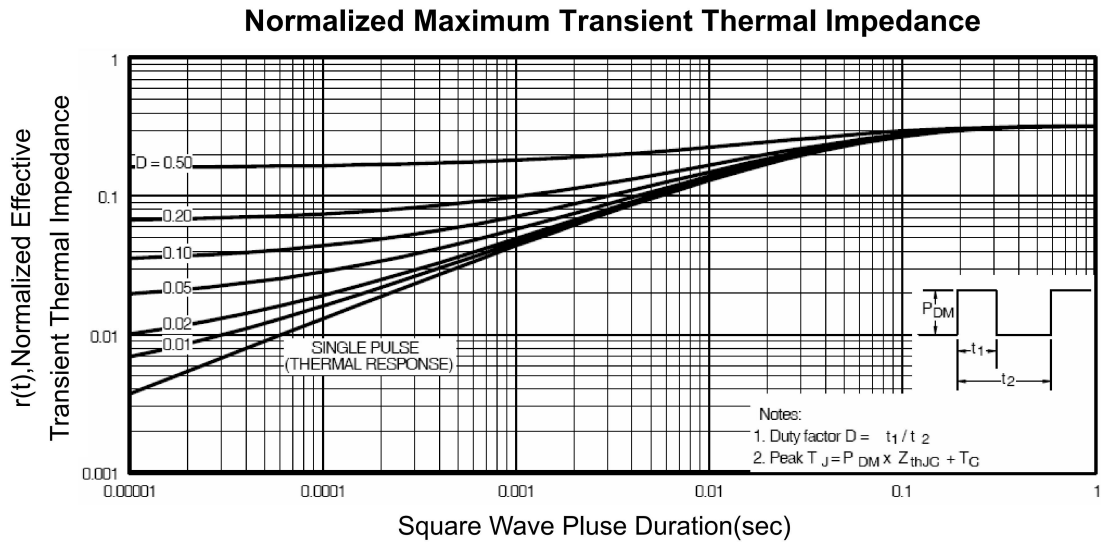
3) Switch Time Test Circuit



Typical Electrical and Thermal Characteristics (Curves)







Package Mechanical DATA

